The Burr-Brown REF102 is a buried-zener-based precision 10V reference. It has better stability and about five times lower output noise than band-gap-based voltage references such as the PMI REF-10. Still, its output noise is about 600µVp-p at a noise bandwidth of 1MHz (the output noise of the PMI REF-10 is about 3,000µVp-p at 1MHz).

You can reduce voltage reference noise by filtering its output. Reduce broadband noise by the square-root of the reduction in noise bandwidth. Filtering the reference to reduce the noise bandwidth by 100/1 (from 1MHz to 10kHz, for example) can reduce the noise by 10/1 (from 600µVp-p to 60µVp-p).

The conventional circuit, shown in Figure 1, uses a single-pole RC filter and a buffer amplifier. One problem with this circuit is that leakage current through the filter capacitor, \( C_1 \), flows through \( R_1 \), resulting in DC error. Furthermore, changes in leakage with temperature result in drift. The relatively low RC time constants often needed dictate large capacitor values prone to this problem.

The improved filter, shown in Figure 2, solves both problems. The improved filter places the RC filter at the output of the buffer amplifier. Reference noise is filtered by a single pole of \( f_{-3dB} = 2 \cdot \pi \cdot R_1 \cdot C_1 \). The \( R_2 \), \( C_2 \) network assures amplifier loop stability. Set \( R_2 \cdot C_2 = 2 \cdot R_1 \cdot C_1 \) to minimize amplifier noise gain peaking. Since buffer amplifier bias current flows through \( R_2 \), keep the value of \( R_2 \) low enough to minimize both DC error and noise due to op amp bias-current noise. Also, load current flows in \( R_1 \). The resulting voltage drop adds to the required swing at the output of the buffer amplifier. Keep the voltage drop across \( R_1 \) low—less than 1V at full load for example—to prevent the amplifier output from swinging too close to its power-supply rail.

With the RC filter at the buffer output, the noise of both the voltage reference and the buffer is filtered. Since the filter is in the feedback loop of the buffer amplifier, \( C_1 \) leakage current errors reacting with \( R_1 \) are divided down to an insignificant level by the loop gain of the buffer amp. The feedback also keeps the DC output impedance of the improved filter near zero. Also, leakage through \( C_2 \) is negligible because the voltage across it is nearly zero.

At high frequency, the output impedance of the improved filter is low due to \( C_1 \). The reactance of a \( 1\mu F \) capacitor is \( 0.16 \Omega \) at 1MHz. For an A/D converter reference, connect \( C_1 \) as close to the reference input pin as possible.
The improved filter can drive large capacitive loads without stability problems. Just keep $(C_{LOAD} + C_1) \cdot R_1 < 0.5 \cdot R_2 \cdot C_2$.

There is one caution with the improved filter. Although the output impedance is low at both high frequencies and DC, it peaks at midband frequencies. Reduced loop gain due to the $R_2, C_2$ network is responsible. A peak output impedance of about $0.7 \cdot R_1$ occurs near the filter pole frequency. If lower midband output impedance is required, $R_1$ must be reduced and $C_1$ increased accordingly. (Condensed from Application Bulletin AB-003. Request PDS-466 for OPA27 and PDS-900 for REF102.)
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